

GPIHV10DK

N-channel 1200V 10A GaN Power HEMT in TO252 Package

Datasheet version 1: Preliminary

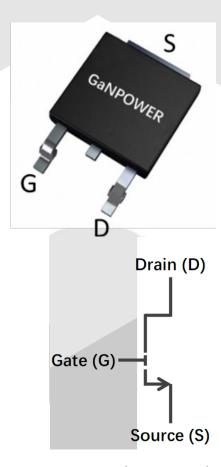
Features

BV _{dss}	R _{dson}	l _{ds}	Qg
1200 V	112 mΩ	7 A	3.5 nC

- Ultra-low RDS(on)
- High dv/dt capability
- Extremely low input capacitance
- Zero Qrr
- Outstanding switching performance
- Low Profile

Applications

- Switching Power Applications
- Server and Telecom Power Application
- EVOBC and DC-DC Converters
- UPS, Inverters, PV



Description

These devices are N-channel 1200 V Power GaN HEMTs based on proprietary E-mode GaN on silicon technology. The resulting product has extremely low on state resistance, very low input capacitance and zero reverse recovery charge making it especially suitable for applications which require superior power density, ultra-high switching frequency and outstanding efficiency.



Device Characteristics

Sta	Static Parameters			Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	V _{gs(TH)}	Gate threshold voltage	V _{ds} =V _{gs} Id=2.5mA	1.2	1.4	1.7	V
2	BV _{dss}	Drain-Source breakdown voltage	V_{gs} =0V I_d < 14 μ A $(T$ =25 $^{\circ}$ C $)$		1200		V
3	l _{dss}	Zero gate voltage drain current, T _C = 25°C	V _{gs} =0V V _{ds} =1200V		14	20	μА
4	l _{gss}	Gate-Source Leakage	$V_{gs} = 6V$ $V_{ds} = 0V$		25	1000	μΑ
5	R _{dson}	Static drain-source on resistance, $T_C = 25^{\circ}C$	V _{gs} =6V I _d =2.5A		112	150	mΩ
6	V_{sd}	Reverse conduction voltage	I _{sd} =1A V _{gs} =0V	1.50	2.50	3.0	V
7	Rg	Gate resistance	f=25Mhz Open drain		2.2		Ω
Dyı	namic Paramet	ers			Test d	ata	
	Parameters		Conditions	Min	Typical	Max	Unit
	C _{iss}	Input capacitance	V _{gs} =0V		105		pf
1	C _{oss}	Output capacitance	V _{ds} =700V		32		pf
	C_{rss}	Reverse transfer capacitance	f=1MHz		5.8		pf
	Q_g	Gate charge	V _{ds} =400V		3.5		nC
3	Q_{gs}	Gate to source charge	I _d =9A		0.6		nC
	Q _{gd}	Gate to drain charge	V_{gs} =6 V		0.8		nC
	-0	· ·					
2	Q _{rr}	Reverse recovery charge			0		nC
		Reverse recovery charge			0 Test d	ata	nC
	Q _{rr}	Reverse recovery charge	Conditions	Min		ata	Unit
	Q _{rr}	Reverse recovery charge		Min	Test d		
Sw	Q _{rr} itching Perform Parameters	Reverse recovery charge	V _{ds} =800V	Min	Test d		Unit
Sw	Q _{rr} itching Perform Parameters t _{d(on)}	Reverse recovery charge Turn-on delay time		Min	Test d Typical		Unit ns



Absolute Max. Ratings

	Symbols	Symbols Parameters		Unit
1	$V_{\text{DS-max}}$	Breakdown voltage transient @ T _{case} =25°C	1500	V
	$V_{\text{DS-max}}$	Breakdown voltage transient @ T _{case} =125°C	1250	V
2	V _{GS-max}	V _{GS-max} Gate to source max. voltage @ T _{case} =25°C		V
3	l _{ds-max}	Drain to source DC current @ T _{case} =25°C	10	А
4	I _{ds-max}	Drain to source DC current @ T _{case} =100°C	8	А
5	dv/dt _{-max}	Drain to source voltage slew rate	150	V/ns
6	T_{J-max}	Max junction temperature	150	°C
7	$T_{S-storage}$	Storage temperature	-55 to 150	°C

Thermal and Soldering Characteristics (Typical)

	Symbols	Parameters	Value	Unit
1	R_{thJC}	Thermal resistance (junction to case)	1.25	°C /W
2	R_{thJA}	Thermal resistance (junction to ambient)	60	°C /W
2	T_{solder}	Reflow soldering temperature	260	°C

Ordering

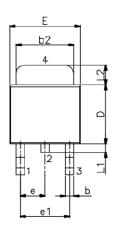
Order Code	Package Type	Packaging Method	Qty
GPIHV10DK	TO-252		

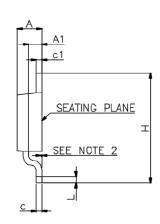


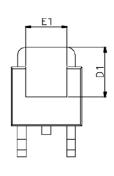
GaNPower International Inc.

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Package Information







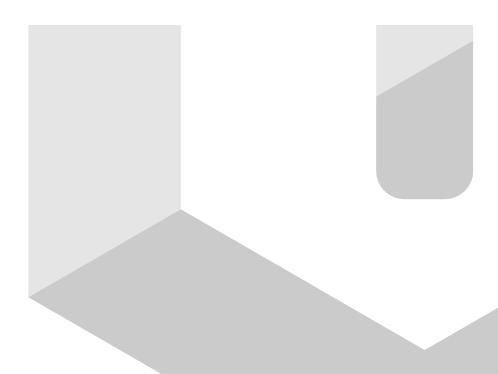
VARIATIONS (ALL DIMENSIONS SHOWN IN INCH)

SYMBOLS	MIN.	MAX.	
Α	0.086	0.094	
A1	0.040	0.050	
Ь	0.024 TYP.		
Ь2	0.205	0.215	
O	0.018	0.023	
c1	0.018	0.023	
D	0.210	0.220	
E	0.250	0.265	
D1	0.180	_	
E1	0.150	_	
Ф	0.090	BSC.	
e1	BSC.		
I	0.370	0.410	
L	0.020	_	
L1	0.025	0.040	
L2	0.06	0.08	
	A A1 B B2 C C C1 D E D1 E1 e e1 H L	A 0.086 A1 0.040 b 0.024 T b2 0.205 c 0.018 c1 0.018 D 0.210 E 0.250 D1 0.180 E1 0.150 e 0.090 e1 0.180 H 0.370 L 0.025	

NOTES:

- 1. JEDEC OUTLINE : TO-252 AB
- 2. 2 MILS SUGGESTED FOR POSITIVE CONTACT AT MOUNTING.







Gan HEMT Frequently Asked Questions

1
O: Can we do
pin to pin switch f
for silicon
MOSFFT or IGBT?

A: The short answer is no. GaN HEMT power devices are far superior than the best silicon devices such as super junction MOSFETs. However, due to different requirements of gate driving voltage and extremely high dv/dt slew rate, special drivers and optimized PCB layouts are recommended to minimize the impact from circuit parasitics. Some packaging forms such as GaNPower's DFN packaged devices offer both sense and force for the source terminal. Also, for traditional TO220 packages, please be advised that the pins are arranged as Gate – Source -Drain, and the thermal pad is connected to the source instead of drain.

- 2 Q: Are GaN power devices reliable?
 - A: GaN power HEMTs have been tested by GaNPower and many other vendors, users and testing facilities to be as reliable (if not better than) silicon counterparts.
- 3 Q: How do GaN power devices compare with SiC?
 - A: Currently GaN power HEMT devices are most suitable for low to medium voltage (\leq 1200V) and power (<20KW) applications. GaN is the ideal choice for high frequency applications. SiC devices are better choice for high voltage and high-power applications (>20KW).
- 4 Q: Do we need to parallel an FRD for applications such as inverters?
 - A: GaN devices are different from silicon MOSFET or IGBT in that they have no inherent PN junction diodes that cause reverse recovery issue. User do not need to parallel an FRD for the purpose of suppressing the body diode reverse recovery effect, since GaN HEMT can operate in both first and third quadrants. However, care should be taken for the dead time powerloss since the Vsd voltage of GaN HEMT is usually close to 2V. This is especially true when a negative gate voltage is applied.
- 5 Q: Can we parallel GaN HEMT devices?
 - A: Yes, GaN HEMT is ideal for paralleling, due to positive temperature coefficient of Rdson and slightly positive temperature coefficient of threshold voltage.
- 6 Q: Where can we find drivers for GaNPower HEMT devices?
 - A: While some of the GaNPower's HEMTs are either monolithically integrated with gate driver or co-packaged with a silicon driver, drivers can be easily found from vendors such as TI and Silicon Lab for either single sided or half-bridge configurations:
 - ✓ TI: LM5114: Single 7.6A Peak Current Low-Side Gate Driver
 - ✓ TI: UCC27611: 5V, 4A/6A Low Side GaN Driver
 - ✓ Maxim: MAX5048C: 7A Sink/3A Source Current, 8ns, SOT23, MOSFET Drive
 - ✓ Fairchild: FAN3122: Single 9-A High-Speed, Low-Side Gate Driver
 - ✓ Silicon Lab: Si827X: 4 Amp ISO driver with High Transient (dv/dt) Immunity